100

110

Start

Identifying M design structures and N physical characteristics of the semiconductor circuit design.

120

For each of the M design structures, determining a fail rate of the design structure and determining whether the fail rate is high or low.

130

For each of the N physical characteristics:

* Flagging the physical characteristic as being likely to contain at least a defect if every design structure of the M design structures in which the physical characteristic is present has a high fail rate, or

* Determining that the physical characteristic should not be flagged as being likely to contain at least a defect if at least one design structure in which the physical characteristic is present has a low fail rate.

Stop

FIG. 1

200

	PC1	PC2	PC3	PC4	PC5	Fail Rate	High Fail Rate
SC1	1	1	0	1	0	80%	1
SC2	0	1	0	1	0	10%	0
SC3	0	1	1	1	1	90%	1
SC4	0	0	0	1	1	15%	0
SC5	0	0	1	1	0	75%	1
SC6	0	0	0	1	0	30%	0
Flagged as being likely to contain at least a defect?	Yes	No	Yes	No	No		

FIG. 2

FIG. 3